

-30V P-Channel Enhancement Mode MOSFET

Description

The AP3407MI uses advanced Trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

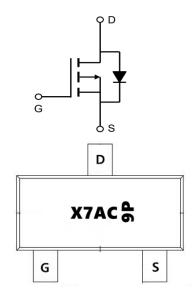
V_{DS} = -30V I_D =-4.8A

 $R_{DS(ON)} < 55m\Omega @ V_{GS}=10V$ (Type: 40mΩ)

Application

Battery protection

Load switch Uninterruptible power supply

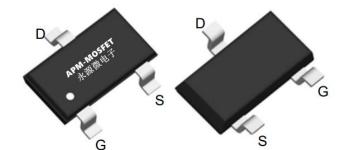


Top View

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Bottom View

04...



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS) 3000			
AP3407MI	SOT23-3L	X7AC 9P				
Absolute Maxim	Absolute Maximum Ratings (T _c =25 [°] Cunless otherwise noted)					
Symbol	Parameter Max.		Units			
VDSS	Drain-Source Voltage	-30	V			
VGSS	Gate-Source Voltage	±20	V			
I⊳@Tc=25℃	Continuous Drain Current, V _{GS} @ -10V ¹	-4.8	A			
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ -10V ¹	-3.3	A			
IDM	Pulsed Drain Current note1	-20.4	A			
PD	Power Dissipation $T_A = 25^{\circ}C$	2.15	W			
RθJA	Thermal Resistance, Junction to Ambient	104	°C/W			
RθJC	Thermal Resistance from Junction to Ambient ²	125	°C/W			
TJ, TSTG	Operating and Storage Temperature Range	-55 to +150	°C			



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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V(BR)DSS	Drain-Source Breakdown Voltage V_{GS} = 0V, I _D = -250µA		-30	-	-	V
IDSS	Zero Gate Voltage Drain Current V _{DS} = -30V, V _{GS} = 0V		-	-	-1	μA
IGSS	Gate-Source Leakage	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
VGS(th)	Gate-Source Threshold voltage	V _{DS} = V _{GS} , I _D = -250µA	-1	-1.5	-2.5	V
RDS(on)	Ducia Occurre en Otata Decistare e 3	V _{GS} = -10V, I _D = -4.1A	-	40	55	
	Drain-Source on-State Resistance ³	V _{GS} = -4.5V, I _D = -3A	-	54	65	mΩ
Ciss	Input Capacitance		-	530	-	pF
Coss	Output Capacitance	$V_{GS} = 0V$, $V_{DS} = -15V$, f = 1.0MHz	-	70	-	
Crss	Reverse Transfer Capacitance		-	56	-	
Qg	Total Gate Charge		-	6.8	-	nC
Qgs	Gate-Source Charge	$V_{GS} = -10V, V_{DS} = -15V,$ $I_D = -4.1A$	-	1.0	-	
Qgd	Gate-Drain Charge	- 104.1A	-	1.4	-	
td(on)	Turn-on Delay Time		-	14	-	
tr	Rise Time	V _{GS} = -10V, V _{DS} = -15V ,	-	61	-	
td(off)	Turn-off Delay time	R _L = 15Ω,R _{GEN} = 2.5Ω	-	19	-	ns
t _f	Fall Time		-	10	-	
VSD	Diode Forward Voltage ³		-	-	-1.2	V
IS	Continuous Source Current	$I_{S} = -4.1A, V_{GS} = 0V$			-4.1	А

Electrical Characteristics (TJ=25°C, unless otherwise noted)

Note :

1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.

2. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%

3. The power dissipation is limited by 150° C junction temperature

4. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.

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Typical Characteristics

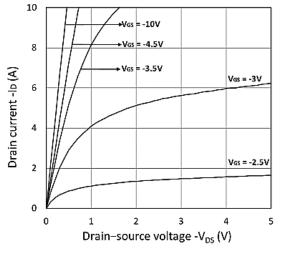


Figure 1. Output Characteristics

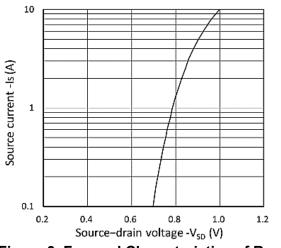


Figure 3. Forward Characteristics of Reverse

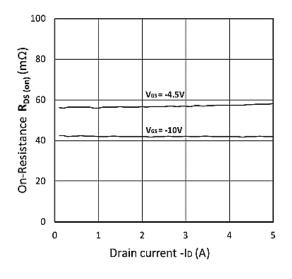


Figure 5. RDS(ON) vs. ID

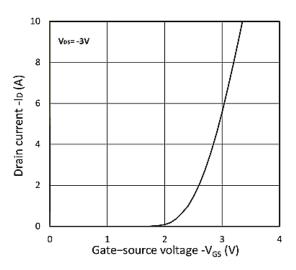
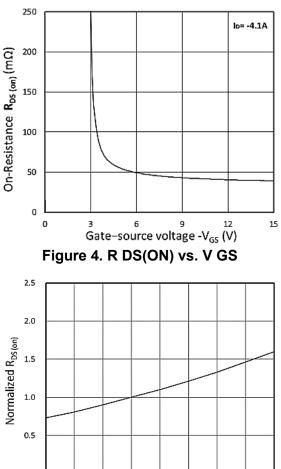


Figure 2. Transfer Characteristics



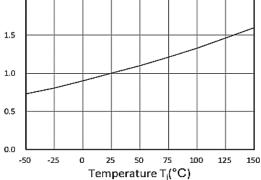


Figure 6. Normalized R DS(on) vs. Temperature



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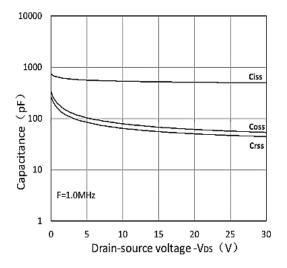
10

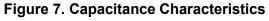
Gate-source voltage -V_{GS} (V)

0

0

Vos = -15V Io= -4.1A







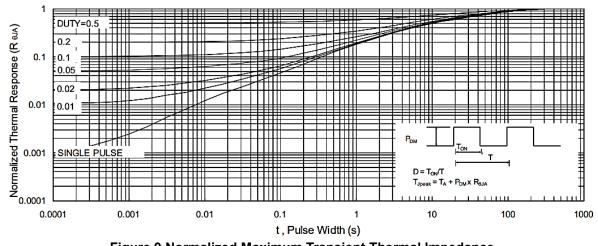
4

Q_g-Toal Gate Charge (nC)

6

8

2





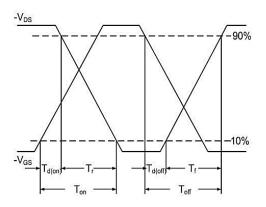


Figure.10 Switching Time Waveform

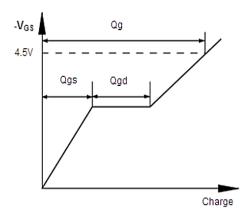
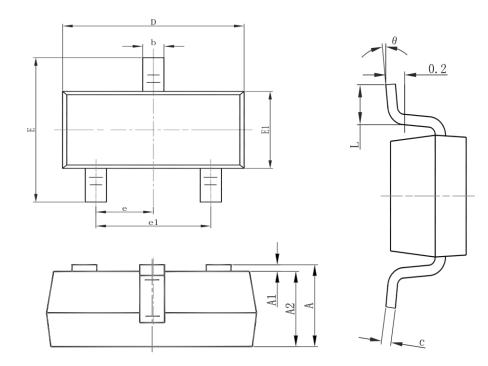


Figure.11 Gate Charge Waveform



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Package Mechanical Data-SOT23-3-SLS-Single



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
А	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
С	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
e	0.950(BSC)		0.03	7(BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°

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Edition	Date	Change
Rve3.9	2018/11/31	Initial release
Rve4.0	2021/12/10	Reduce internal RDS

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AP3407MI RVE1.0

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